



Docket No. 49481 (70551)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANT: M. Hatanaka et al.

U.S. SERIAL NO.: 09/471,829

GROUP: 2877

FILED: December 23, 1999

EXAMINER: S. Turner

FOR: APPARATUS AND METHOD FOR MEASURING THE THICKNESS
OF A THIN FILM VIA THE INTENSITY OF REFLECTED LIGHT

CERTIFICATE OF EXPRESS MAILING

I hereby certify that this paper (along with any paper referred to as being attached or enclosed) is being deposited with the United States Postal Service on this date September 21, 2005 in an envelope as "Express Mail Post Office to Addressee," mailing Label Number EV711314551US addressed to the: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

By: _____

Michelle Chicos
Michelle P. Chicos

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

AMENDMENT

Applicants are in receipt of the Final Office Action dated April 21, 2005 of the above-referenced application. A Request for Continued Examination (RCE) and a two-month extension of time are submitted herewith. Please amend the application as follows:

Amendments to the claims are reflected in the listing of claims which begins on page 2 of this paper.

Remarks begin on page 7 of this paper.